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					Examiner Name	James A. Menefee
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary) Sheet 6 of 6 Attorney Docket Number 42P14879 NON PATENT LITERATURE DOCUMENTS Examiner Initials* No1 Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where publisher. JM 71 ANDALKAR, A., et al., "Improved External Cavity Design for Cesium D1 (894 nm) Diode Laser," Review of Scientific Instruments, 2000 American Institute of Physics, November 2000, vol. 71, no. 11, pp. 4029-4031. JM 72 ICHIHASHI, Y., et al., "130 GHz Frequency Sweep Over a 30 nm Tuning Range Without Mode Hopping by an External-Cavity Semiconductor Laser," IEICE Transactions on Communications, June 1992; Tokyo, Japan, vol. E75-8, no. 6, pp. 521-523. JM 73 KETELSEN, L.J.P., "Simple Technique for Measuring Cavity Loss in Semiconductor Lasers," Electronics Letters, August 18, 1994, vol. 30, no. 17, pp. 1422-1423. JM 74 SHTENGEL, G.E., et al., "Internal Optical Loss Measurements in 1.3 \(\mu\) m InGaASP Lasers," Electronics Letters, July 6, 1995, vol. 31, no. 14, pp. 1157-1159.	Substitute for Form 1449/PTO					Complete if Known			
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